



S2: (19) (UHLMANN near2 GREGORY).in.
S3: (16) (ADAMS near2 CHAD).in.
S5: (2160) (redundan\$2 or replac\$5 or spar\$5 or substitut\$5) adj2 (wordline or word-line or (word...
S7: (37) \$3compar\$8 with (current adj2 address) with (defect\$4 adj2 address)
S8: (9) \$3match\$4 with (current adj2 address) with (defect\$4 adj2 address)
S11: (62892) \$3compar\$8 with address
S12: (30661) \$3match\$4 with address
S13: (462) S5 same S11
S14: (213) S5 same S12
S15: (1549) (disabl\$4 or deactivat\$4 or inactivat\$4) adj5 (wordline or word-line or (word adj line))
S16: (28) S15 same S13
S17: (18) S15 same S14
S20: (568) deactivat\$4 adj2 driver
S21: (1622) (redundan\$2 or replac\$5 or spar\$5 or substitut\$5) adj2 driver
S22: (78691) S11 or S12
S23: (71) S22 and S20
S24: (259) S22 and S21
S25: (84) S22 same S21
S30: (175) S24 not S25
S31: (6508) 365/200
S32: (2624) 365/189.07
S33: (5669) 365/230.06
S34: (84594) "365"/\$6
S36: (544) S13 or S14
S37: (278) S36 and S31
S38: (54) S36 and S32
S39: (115) S36 and S33
S40: (454) S36 and S34
S41: (227) S37 not (S23 or S25 or S16 or S17)
S43: (146) S40 not (S37 or S38 or S39)

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1	<input type="checkbox"/>	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5930183 A	19990727	Kojima; Kazumi et al.	365/200	365/189.05; 365/230.03		Semiconductor memory device	13	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
2	<input type="checkbox"/>	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6272057 B1	20010807	Koshikawa; Yasuji	365/200	365/203		Semiconductor memory device	17	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
3	<input type="checkbox"/>	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6522595 B2	20030218	Carson; Bryan C. et al.	365/225.7	365/200		Methods for forming and programming aligned fuses, diodes	14	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
4	<input type="checkbox"/>	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6694448 B2	20040217	Callahan; John M.	714/7	365/201		SRAM row redundancy	15	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>

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